$2\ \text{K}\times 8\ \text{CMOS}$ Dual Port RAM 3.3 Volt

Introduction

The L67132/67142 are very low power CMOS dual port static RAMs organized as 2048×8 . They are designed to be used as a stand-alone 8 bit dual port RAM or as a combination MASTER/SLAVE dual port for 16 bits or more width systems. The MHS MASTER/SLAVE dual port approach in memory system applications results in full speed, error free operation without the need for additional discrete logic.

Master and slave devices provide two independent ports with separate control, address and I/O pins that permit independent, asynchronous access for reads and writes to any location in the memory. An automatic power down feature controlled by \overline{CS} permits the onchip circuitry of each port in order to enter a very low stand by power mode.

Using an array of eight transistors (8T) memory cell and fabricated with the state of the art 1.0 μ m lithography named SCMOS, the L67132/67142 combine an extremely low standby supply current (typ = 1.0 μ A) with a fast access time at 45 ns over the full temperature range. All versions offer battery backup data retention capability with a typical power consumption at less than 5 μ W.

For military/space applications that demand superior levels of performance and reliability the L67132/67142 is processed according to the methods of the latest revision of the MIL STD 883 (class B or S) and/or ESA SCC 9000.

Features

- Single 3.3 V \pm 0.3 volt power supply
- Fast access time 45(*) ns to 70 ns
- 67132L/67142L low power
 67132V/67142V very low power
- Expandable data bus to 16 bits or more using master/slave devices when using more than one device
- (*) Preliminary

- On chip arbitration logic
- $\overline{\text{BUSY}}$ output flag on master
- **BUSY** input flag on slave
- Fully asynchronous operation from either port
- Battery backup operation : 2 V data retention



Interface

Pin Configuration



Block Diagram



Note: 1. L 67132 (MASTER) : BUSY is open drain output and requires pullup resistor L 67142 (SLAVE) : BUSY in input

Pin Names

LEFT PORT	RIGHT PORT	NAMES		
\overline{CS}_L	\overline{CS}_R	Chip select		
R/\overline{W}_L	R/\overline{W}_R	Write Enable		
OEL	\overline{OE}_R	Output Enable		
A _{0L - 10L}	A_{0R-10R}	Address		
I/O _{0L - 7L}	I/O _{0R - 7R}	Data Input/Output		
BUSYL	BUSY _R	Busy Flag		
V	VCC			
GN	ND	Ground		

Functional Description

The L67132/67142 has two ports with separate control, address and I/0 pins that permit independent read/write access to any memory location. These devices have an automatic power-down feature controlled by \overline{CS} . \overline{CS} controls on-chip power-down circuitry which causes the port concerned to go into stand-by mode when not selected (\overline{CS} high). When a port is selected access to the full memory array is permitted. Each port has its own Output Enable control (\overline{OE}). In read mode, the port's \overline{OE} turns the Output drivers on when set LOW. Non-conflicting READ/WRITE conditions are illustrated in table 1.

Arbitration Logic

The arbitration logic will resolve an address match or a chip select match down to a minimum of 5 ns and determine which port has access. In all cases, an active $\overline{\text{BUSY}}$ flag will be set for the inhibited port.

The $\overline{\text{BUSY}}$ flags are required when both ports attempt to access the same location simultaneously.Should this conflict arise, on-chip arbitration logic will determine which port has access and set the $\overline{\text{BUSY}}$ flag for the inhibited port. $\overline{\text{BUSY}}$ is set at speeds that allow the processor to hold the operation with its associated address and data. It should be noted that the operation is invalid for the port for which $\overline{\text{BUSY}}$ is set LOW. The inhibited port will be given access when $\overline{\text{BUSY}}$ goes inactive.

A conflict will occur when both left and right ports are active and the two addresses coincide. The on-chip arbitration determines access in these circumstances. Two modes of arbitration are provided : (1) if the addresses match and are valid before \overline{CS} on-chip control logic arbitrates between \overline{CS}_L and \overline{CS}_R for access ; or (2) if the \overline{CS} are low before an address match, on-chip control logic arbitrates between the left and right addresses for

access (refer to table 2). The inhibited port's $\overline{\text{BUSY}}$ flag is set and will reset when the port granted access completes its operation in both arbitration modes.

Data Bus Width Expansion

Master/Slave Description

Expanding the data bus width to 16 or more bits in a dual-port RAM system means that several chips may be active simultaneously. If every chip has a hardware arbitrator, and the addresses for each chip arrive at the same time one chip may activate its L BUSY signal while another activates its R BUSY signal. Both sides are now busy and the CPUs will wait indefinitely for their port to become free.

To overcome this "Busy Lock-Out" problem, MHS has developed a MASTER/SLAVE system which uses a single hardware arbitrator located on the MASTER. The SLAVE has BUSY inputs which allow direct interface to the MASTER with no external components, giving a speed advantage over other systems.

When dual-port RAMs are expanded in width, the SLAVE RAMs must be prevented from writing until the BUSY input has been settled. Otherwise, the SLAVE chip may begin a write cycle during a conflict situation. On the opposite, the write pulse must extend a hold time beyond BUSY to ensure that a write cycle occurs once the conflict is resolved. This timing is inherent in all dual-port memory systems where more than one chip is active at the same time.

The write pulse to the SLAVE must be inhibited by the MASTER's maximum arbitration time. If a conflict then occurs, the write to the SLAVE will be inhibited because of the MASTER's <u>BUSY</u> signal.

Truth Table

Table 1 : Non Contention Read/Write Control⁽⁴⁾

	LEFT OR RI	GHT PORT ⁽¹⁾		DUNCTION
R/W	CS	ŌĒ	D0-7	FUNCTION
Х	Н	Х	Z	Port Disabled and in Power Down Mode. ICCSB or ICCSB1
L	L	Х	DATA _{IN}	Data on Port Written into memory ⁽²⁾
Н	L	L	DATA _{OUT}	Data in Memory Output on Port ⁽³⁾
Н	L	Н	Z	High Impedance Outputs

Notes: 1. $A_{OL} - A_{10L} \neq A_{0R} - A_{10R}$. 2. If $\overline{BUSY} = L$, data is not written.

3. If $\overline{\text{BUSY}} = L$, data may not be valid, see t_{WDD} and t_{DDD} timing.

4. H = HIGH, L = LOW, X = DON'T CARE, Z = HIGH IMPEDANCE.

Table 2 : Arbitration⁽⁵⁾

LEFT	PORT	RIGHT	PORT	FLAGS		FUNCTION
\overline{CS}_L	$A_{0L}-A_{10L}$	C S _R	$A_{0L} - A_{10R}$	BUSYL	BUSY _R	FUNCTION
Н	Х	Н	Х	Н	Н	No Contention
L	Any	Н	Х	Н	Н	No Contention
Н	Х	L	Any	Н	Н	No Contention
L	$\neq A_{0R} - A_{10R}$	L	$\neq A_{0L} - A_{10L}$	Н	Н	No Contention
ADDRESS ARE	BITRATION WIT	H CE LOW BEF	ORE ADDRESS M	ІАТСН		
L	LV5R	L	LV5R	Н	L	L–Port Wins
L	RV5L	L	RV5L	L	Н	R–Port Wins
L	Same	L	Same	Н	L	Arbitration Resolved
L	Same	L	Same	L	Н	Arbitration Resolved
CS ARBITRAT	ION WITH ADD	RESS MATCH BI	EFORE CS			
LL5R	$=A_{0R}-A_{10R}$	LL5R	$=A_{0L}-A_{10L}$	Н	L	L–Port Wins
RL5L	$=A_{0R}-A_{10R}$	RL5L	$= A_{0L} - A_{10L}$	L	Н	R–Port Wins
LW5R	$= A_{0R} - A_{10R}$	LW5R	$=A_{0L}-A_{10L}$	Н	L	Arbitration Resolved
LW5R	$= A_{0R} - A_{10R}$	LW5R	$=A_{0L}-A_{10L}$	L	Н	Arbitration Resolved

Notes : 5. X = DON'T CARE, L = LOW, H = HIGH.

 $LV5R = Left Address Valid \ge 5 ns before right address.$

 $RV5L = Right address Valid \ge 5 ns before left address.$

Same = Left and Right Addresses match within 5 ns of each other.

 $LL5R = Left \overline{CS} = LOW \ge 5$ ns before Right \overline{CS} .

 $RL5L = Right \overline{CS} = LOW \ge 5$ ns before left \overline{CS} .

LW5R = Left and Right \overline{CS} = LOW within 5 ns of each other.

Electrical Characteristics

Absolute Maximum Ratings

* Notice

Input or output voltage applied : . . . (GND –0.3 V) to (VCC + 0.3 V) Storage temperature : $-65^{\circ}C$ to $+150^{\circ}C$ Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extented periods may affect reliability.

OPERATING RANGE	OPERATING SUPPLY VOLTAGE	OPERATING TEMPERATURE			
Military	$V_{CC} = 3.3 V \pm 0.3 V$	– 55 °C to + 125 °C			
Automotive	$V_{CC} = 3.3 V \pm 0.3 V$	- 40 °C to + 125 °C			
Commercial	$V_{CC} = 3.3 V \pm 0.3 V$	0 °C to + 70 °C			
Industrial	$V_{CC} = 3.3 V \pm 0.3 V$	- 40 °C to + 85 °C			

DC Parameters

			L67132/67142-4 5		L67132/67142–5 5		L67132/67142-7 0			
Parameter	Description		СОМ	IND MIL AUTO	сом	IND MIL AUTO	сом	IND MIL AUTO	Unit	Value
			PRELIMINARY			AUIO		AUIO		
I _{CCSB (6)}	Standby supply current	V	1	1	1	1	1	1	mA	Max
	(Both ports TTL level inputs)	L	5	10	5	10	5	10	mA	Max
I _{CCSB1 (7)}	Standby supply current	V	10	20	10	20	10	20	μΑ	Max
	(Both ports CMOS level inputs)	L	100	200	100	200	100	200	μΑ	Max
I _{CCOP (8)}	Operating supply current	V	80	90	70	80	60	70	mA	Max
	(Both ports active)	L	80	100	70	90	60	80	mA	Max
I _{CCOP1 (9)}	Operating supply current	V	50	55	40	45	35	40	mA	Max
	(One port active – One port standby)	L	60	65	50	55	45	50	mA	Max

Notes : 6. $\overline{CS}_L = \overline{CS}_R \ge 2.2 \text{ V.}$

7. $\overline{\text{CS}}_{\text{L}} = \overline{\text{CS}}_{\text{R}} \ge \text{VCC} - 0.2 \text{ V}.$

8. Both ports active – Maximum frequency – Outputs open – \overline{OE} = VIH.

9. One port active (f = MAX) – Output open – One port stand-by TTL or CMOS Level inputs – $\overline{CS}_{R} \ge 2.2$ V.

PARAMETER	DESCRIPTION	L67132–45/55/70 L67142–45/55/70	UNIT	VALUE
II/O ₍₁₀₎	Input/Output leakage current	± 10	μΑ	Max
VIL ₍₁₁₎	Input low voltage	0.7	V	Max
VIH ₍₁₁₎	Input high voltage	1.8	V	Min
VOL(12)	Output low voltage (I/O ₀ –I/O ₇)	0.5	V	Max
VOL(13)	Open drain output low voltage (BUSY)	0.5	V	Max
VOH(12)	Output high voltage	1.5	V	Min
C IN(17)	Input capacitance	5	pF	Max
C OUT ₍₁₇₎	Output capacitance	7	pF	Max

10. $V_{CC} = 5$ V, Vin = Gnd to V_{CC} , $\overline{CS} = VIH$, Vout = 0 to V_{CC} . Notes :

11. VIH max = V_{CC} + 0.3 V, VIL min – 0.3 V or –1 V pulse width 50 ns. 12. V_{CC} min, IOL = 4 mA, IOH = –4 mA.

13. $I_{OL} = 16 \text{ mA}.$

Data-Retention Mode

MHS CMOS RAMs are designed with battery backup in mind. Data retention voltage and supply current are guaranteed over temperature. The following rules insure data retention :

1 – Chip select (\overline{CS}) must be held high during data retention ; within Vcc to VCC_{DR}.

Timing

 $2-\overline{CS}$ must be kept between V_{CC} – 0.2 V and 70 % of Vcc during the power up and power down transitions.

3 - The RAM can begin operation > tRC after Vcc reaches the minimum operating voltage (3 volts).



		MA		
PARAMETER	TEST CONDITIONS (14)	СОМ	MIL IND AUTO	UNIT
ICC _{DR1}	@ VCC _{DR} = 2 V	10	20	μΑ

Notes : 14. $\overline{CS} = Vcc$, Vin = Gnd to Vcc.

AC Test Conditions

Input Pulse Levels : GND to 3.0 V Input Rise/Fall Times : 5 ns Input Timing Reference Levels : 1.5 V

Figure 1. Output Load.



* Including scope and jig

Output Reference Levels : 1.5 V Output Load : see figures 1, 2





AC Parameters

READ C	YCLE						L67132–70 L67142–70		
SYMBOL (19)	SYMBOL (20)	PARAMETER	MIN. PRELIN	MAX. MINARY	MIN.	MAX.	MIN.	MAX.	UNIT
TAVAVR	t _{RC}	Read cycle time	45	-	55	-	70	-	ns
TAVQV	t _{AA}	Address access time	_	45	_	55	_	70	ns
TELQV	t _{ACS}	Chip Select access time (18)	_	45	_	55	_	70	ns
TGLQV	t _{AOE}	Output enable access time	_	30	_	35	_	40	ns
TAVQX	t _{OH}	Output hold from address change	0	_	0	_	0	_	ns
TELQZ	t _{LZ}	Output low Z time (16, 17)	5	_	5	-	5	_	ns
TEHQZ	t _{HZ}	Output high Z time (16, 17)	-	20	-	30	_	35	ns
TPU	t _{PU}	Chip Select to power up time (17)	0	_	0	_	0	_	ns
TPD	t _{PD}	Chip disable to power down time (17)	-	50	-	50	_	50	ns

Notes: 16. Transition is measured \pm 500 mV from low or high impedance voltage with load (figures 1 and 2).

17. This parameter is guaranteed but not tested.

18. To access RAM $\overline{CS} = VIL$.

19. STD symbol.

20. ALT symbol.

Timing Waveform of Read Cycle nº 1, Either Side (21, 22, 24)



Timing Waveform of Read Cycle nº 2, Either Side (21, 23, 25)



Notes : 21. R/\overline{W} is high for read cycles.

22. Device is continuously enabled, $\overline{CS} = VIL$.

23. Addresses valid prior to or coincident with \overline{CS} transition low.

24. $\overline{OE} = V_{IL}$.

25. To access RAM, $\overline{CS} = V_{IL}$.

AC Parameters

WRITE (CYCLE			32–45 42–45	L67132–55 L67142–55		L67132–70 L67142–70		
SYMBOL (30)	SYMBOL (31)	PARAMETER	MIN. PRELIN	MAX. MINARY	MIN.	MAX.	MIN.	MAX.	UNIT
TAVAVW	t _{WC}	Write cycle time	45	_	55	_	70	_	ns
TELWH	t _{SW}	Chip select to end of write (28)	35	_	40	_	45	_	ns
TAVWH	t _{AW}	Address valid to end of write	35	_	40	_	45	_	ns
TAVWL	t _{AS}	Address Set-up Time	0	_	0	_	0	_	ns
TWLWH	t _{WP}	Write Pulse Width	35	_	40	_	45	_	ns
TWHAX	t _{WR}	Write Recovery Time	0	_	0	-	0	_	ns
TDVWH	t _{DW}	Data Valid to end of write	25	_	25	-	30	_	ns
TGHQZ	t _{HZ}	Output high Z time (26, 27)	-	20	_	30	_	40	ns
TWHDX	t _{DH}	Data hold time (29)	0	_	0	_	0	_	ns
TWLQZ	t _{WZ}	Write enable to output in high Z (26, 27)	-	20	_	30	_	40	ns
TWHQX	t _{OW}	Output active from end of write (26, 27, 29)	0	_	0	-	0	_	ns

Notes: 26. Transition is measured \pm 500 mV from low or high impedance voltage with load (figures 1 and 2).

27. This parameter is guaranteed but not tested.

28. To access RAM \overline{CS} = VIL.

This condition must be valid for entire t_{SW} time.

 The specification for t_{DH} must be met by the device supplying write data to the RAM under all operating conditions. Although t_{DH} and t_{OW} values vary over voltage and temperature, the actual t_{DH} will always be smaller than the actual t_{OW}.

30. STD symbol.

31. ALT symbol.

Timing Waveform of Write Cycle nº 1, R/W Controlled Timing (32, 33, 34, 38)



Timing Waveform of Write Cycle nº 2, CS Controlled Timing (32, 33, 34, 36)



Notes: 32. R/\overline{W} must be high during all address transitions.

- 33. A write occurs during the overlap (t_{SW} or t_{WP}) of a low \overline{CS} and a low R/\overline{W} .
- 34. t_{WR} is measured from the earlier of \overline{CS} or R/\overline{W} going high to the end of write cycle.
- 35. During this period, the I/O pins are in the output state, and input signals must not be applied.
- 36. If the \overline{CS} low transition occurs simultaneously with or after the R/\overline{W} low transition, the outputs remain in the high impedance state.
- 37. Transition is measured \pm 500 mV from steady state with a 5 pF load (including scope and jig). This parameter is sampled and not 100 % tested.
- 38. If \overline{OE} is low during a R/\overline{W} controlled write cycle, the write pulse width must be the larger of t_{WP} or $(t_{WZ} + t_{DW})$ to allow the I/O drivers to turn off and data to be placed on the bus for the required t_{DW} . If \overline{OE} is high during an R/\overline{W} controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified t_{WP} .
- 39. To access RAM, $\overline{CS} = VIL$.

AC Parameters

SYMBOL	PARAMETER	L67132-45 L67142-45		L67132–55 L67142–55		L67132–70 L67142–70		UNIT
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
BUSY TIMIN	G (For L 67132 only)							
t _{BAA}	BUSY Access time to address	-	35	-	45	Ι	50	ns
t _{BDA}	BUSY Disable time to address	-	35	-	40	Ι	40	ns
t _{BAC}	BUSY Access time to Chip Select	-	30	-	35	Ι	50	ns
t _{BDC}	BUSY Disable time to Chip Select	-	25	-	30	Ι	40	ns
t _{WDD}	Write Pulse to data delay (40)	_	70	-	80	-	90	ns
t _{DDD}	Write data valid to read data delay (40)	_	45	-	55	Ι	70	ns
t _{APS}	Arbitration priority set-up time (41)	5	-	5	-	5	_	ns
t _{BDD}	BUSY disable to valid data	-	Note 42	-	Note 42	Ι	Note 42	ns
BUSY TIMIN	G (For L 67142 only)							
t _{WB}	Write to $\overline{\text{BUSY}}$ input (43)	0	-	0	-	0	_	ns
t _{WH}	Write hold after $\overline{\text{BUSY}}$ (44)	20	-	30	-	30	-	ns
t _{WDD}	Write pulse to data delay (45)	-	70	-	80	-	90	ns
t _{DDD}	Write data valid to read data delay (45)	-	45	-	55	-	70	ns

Notes: 40. Port-to-port delay through RAM cells from writing port to reading port, refer to "Timing Waveform of Read with BUSY (For L67132 only)".

41. To ensure that the earlier of the two ports wins.

42. t_{BDD} is a calculated parameter and is the greater of 0, $t_{WDD} - t_{WP}$ (actual) or $t_{DDD} - t_{DW}$ (actual).

43. To ensure that the write cycle is inhibited during contention.

44. To ensure that a write cycle is completed after contention.

 Port-to-port delay through RAM cells from writing port to reading port, refer to "Timing Waveforms of Read with Port to port delay (For L67142 only)".



Timing Waveform of Read with BUSY (46, 47, 48) (For L 67132)



Notes : 46. To ensure that the earlier of the two port wins.

47. Write cycle parameters should be adhered to, to ensure proper writing.

48. Device is continuously enabled for both ports.

49. \overline{OE} at L for the reading port.

Timing Waveform of Write with Port-to-port ^(50, 51, 52) (For L 67142 only)



Notes : 50. Assume $\overline{\text{BUSY}} = H$ for the writing port, and $\overline{\text{OE}} = L$ for the reading port.

- 51. Write cycle parameters should be adhered to, to ensure proper writing.
 - 52. Device is continuously enabled for both ports.



Timing Waveform of Write with $\overline{\text{BUSY}}$ (For L 67132)



Timing Waveform of Contention Cycle nº 1, CS Arbitration (For L 67132 only)



Timing Waveform of Contention Cycle n^{o} 2, Address Valid Abritration (For L 67132 only) $^{(53)}$

Left Address Valid First :



Right Address Valid First :



Note : 53. $\overline{CS}_L = \overline{CS}_R = V_{IL}$

16 Bit Master/Slave Dual-port Memory Systems



Note: 54. No arbitration in L 67142 (SLAVE). BUSY-IN inhibits write in L 67142 (SLAVE).

Ordering Information



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